

Notice of References Cited	Application/Control No. 10/616,508		Applicant(s)/Patent Under Reexamination SHIN, HYEON SANG	
	Examiner James M. Mitchell		Art Unit 2813	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,222,225	04-2001	Nakamura et al.	257/315
	B	US-6,649,472	11-2003	Hsieh, Chia-Ta	438/257
	C	US-6,620,740	09-2003	Thakur, Randhir P. S.	438/771
	D	US-6,391,722	05-2002	Koh, Chao-Ming	438/264
	E	US-2003/0068860	04-2003	Rabkin et al.	438/257
	F	US-2003/0119257	06-2003	Dong et al.	438/257
	G	US-6,221,715	04-2001	Chen, Bin-Shing	438/257
	H	US-6,355,539	03-2002	Lai et al.	438/424
	I	US-6,323,085	11-2001	Sandhu et al.	438/257
	J	US-6,197,637	03-2001	Hsu et al.	438/257
	K	US-6,743,675	06-2004	Ding, Yi	438/257
	L	US-2002/0072170	06-2002	Lam, Chung Hon	438/239
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.